



<p>Searched</p> 	<p>Application/Control No.</p> <p>10661816</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>MUCHOW ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
307	72	10/12/2006	HK
320	101	10/12/2006	HK

U.S. Patent and Trademark Office	Part of Paper No.: 20061012
----------------------------------	-----------------------------

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10661816	MUCHOW ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/12/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/18/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/19/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/20/2006	HK
361/600+; 220/\$ (consulted Boris Chervinsky)	10/19/2006	HK
290/\$ (consulted Joseph Waks)	10/20/2006	HK
U.S. Patent and Trademark Office		Part of Paper No.: 20061012